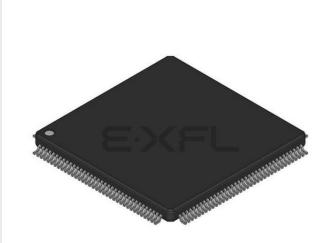
E·XFL

Altera - EP20K60ETC144-2N Datasheet



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	2560
Number of Logic Elements/Cells	2560
Total RAM Bits	32768
Number of I/O	92
Number of Gates	162000
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep20k60etc144-2n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

General Description

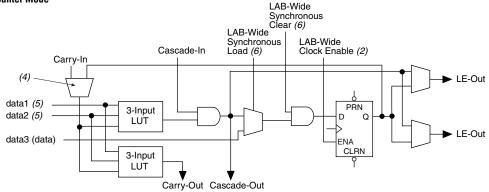
APEX[™] 20K devices are the first PLDs designed with the MultiCore architecture, which combines the strengths of LUT-based and productterm-based devices with an enhanced memory structure. LUT-based logic provides optimized performance and efficiency for data-path, registerintensive, mathematical, or digital signal processing (DSP) designs. Product-term-based logic is optimized for complex combinatorial paths, such as complex state machines. LUT- and product-term-based logic combined with memory functions and a wide variety of MegaCore and AMPP functions make the APEX 20K device architecture uniquely suited for system-on-a-programmable-chip designs. Applications historically requiring a combination of LUT-, product-term-, and memory-based devices can now be integrated into one APEX 20K device.

APEX 20KE devices are a superset of APEX 20K devices and include additional features such as advanced I/O standard support, CAM, additional global clocks, and enhanced ClockLock clock circuitry. In addition, APEX 20KE devices extend the APEX 20K family to 1.5 million gates. APEX 20KE devices are denoted with an "E" suffix in the device name (e.g., the EP20K1000E device is an APEX 20KE device). Table 8 compares the features included in APEX 20K and APEX 20KE devices.

LAB-Wide Normal Mode (1) Clock Enable (2) Carry-In (3) Cascade-In LE-Out data1 data2 PRN 4-Input D Q LUT data3 LE-Out ENA data4 CLRN Cascade-Out LAB-Wide Arithmetic Mode Clock Enable (2) Carry-In Cascade-In LE-Out PRN data1 Q D 3-Input data2 LUT LE-Out ENA CLRN 3-Input LUT Cascade-Out Carry-Out

Figure 8. APEX 20K LE Operating Modes





Notes to Figure 8:

- (1) LEs in normal mode support register packing.
- (2) There are two LAB-wide clock enables per LAB.
- (3) When using the carry-in in normal mode, the packed register feature is unavailable.
- (4) A register feedback multiplexer is available on LE1 of each LAB.
- (5) The DATA1 and DATA2 input signals can supply counter enable, up or down control, or register feedback signals for LEs other than the second LE in an LAB.
- (6) The LAB-wide synchronous clear and LAB wide synchronous load affect all registers in an LAB.

Normal Mode

The normal mode is suitable for general logic applications, combinatorial functions, or wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in are inputs to a four-input LUT. The Quartus II software Compiler automatically selects the carry-in or the DATA3 signal as one of the inputs to the LUT. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. LEs in normal mode support packed registers.

Arithmetic Mode

The arithmetic mode is ideal for implementing adders, accumulators, and comparators. An LE in arithmetic mode uses two 3-input LUTs. One LUT computes a three-input function; the other generates a carry output. As shown in Figure 8, the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, when implementing an adder, this output is the sum of three signals: DATA1, DATA2, and carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports simultaneous use of the cascade chain. LEs in arithmetic mode can drive out registered and unregistered versions of the LUT output.

The Quartus II software implements parameterized functions that use the arithmetic mode automatically where appropriate; the designer does not need to specify how the carry chain will be used.

Counter Mode

The counter mode offers clock enable, counter enable, synchronous up/down control, synchronous clear, and synchronous load options. The counter enable and synchronous up/down control signals are generated from the data inputs of the LAB local interconnect. The synchronous clear and synchronous load options are LAB-wide signals that affect all registers in the LAB. Consequently, if any of the LEs in an LAB use the counter mode, other LEs in that LAB must be used as part of the same counter or be used for a combinatorial function. The Quartus II software automatically places any registers that are not used by the counter into other LABs.

Table 9. AP	EX 20K	Routing S	cheme								
Source	Destination										
	Row I/O Pin	Column I/O Pin	LE	ESB	Local Interconnect	MegaLAB Interconnect	Row FastTrack Interconnect	Column FastTrack Interconnect	FastRow Interconnect		
Row I/O Pin					✓	\checkmark	\checkmark	✓			
Column I/O Pin								~	✓ (1)		
LE					\checkmark	\checkmark	\checkmark	\checkmark			
ESB					 Image: A set of the set of the	\checkmark	~	~			
Local Interconnect	~	~	~	~							
MegaLAB Interconnect					~						
Row FastTrack Interconnect						~		~			
Column FastTrack Interconnect						~	~				
FastRow Interconnect					✓ (1)						

Note to Table 9:

(1) This connection is supported in APEX 20KE devices only.

Product-Term Logic

The product-term portion of the MultiCore architecture is implemented with the ESB. The ESB can be configured to act as a block of macrocells on an ESB-by-ESB basis. Each ESB is fed by 32 inputs from the adjacent local interconnect; therefore, it can be driven by the MegaLAB interconnect or the adjacent LAB. Also, nine ESB macrocells feed back into the ESB through the local interconnect for higher performance. Dedicated clock pins, global signals, and additional inputs from the local interconnect drive the ESB control signals.

In product-term mode, each ESB contains 16 macrocells. Each macrocell consists of two product terms and a programmable register. Figure 13 shows the ESB in product-term mode.

ESBs can implement synchronous RAM, which is easier to use than asynchronous RAM. A circuit using asynchronous RAM must generate the RAM write enable (WE) signal, while ensuring that its data and address signals meet setup and hold time specifications relative to the WE signal. In contrast, the ESB's synchronous RAM generates its own WE signal and is self-timed with respect to the global clock. Circuits using the ESB's selftimed RAM must only meet the setup and hold time specifications of the global clock.

ESB inputs are driven by the adjacent local interconnect, which in turn can be driven by the MegaLAB or FastTrack Interconnect. Because the ESB can be driven by the local interconnect, an adjacent LE can drive it directly for fast memory access. ESB outputs drive the MegaLAB and FastTrack Interconnect. In addition, ten ESB outputs, nine of which are unique output lines, drive the local interconnect for fast connection to adjacent LEs or for fast feedback product-term logic.

When implementing memory, each ESB can be configured in any of the following sizes: 128×16 , 256×8 , 512×4 , $1,024 \times 2$, or $2,048 \times 1$. By combining multiple ESBs, the Quartus II software implements larger memory blocks automatically. For example, two 128×16 RAM blocks can be combined to form a 128×32 RAM block, and two 512×4 RAM blocks can be combined to form a 512×8 RAM block. Memory performance does not degrade for memory blocks up to 2,048 words deep. Each ESB can implement a 2,048-word-deep memory; the ESBs are used in parallel, eliminating the need for any external control logic and its associated delays.

To create a high-speed memory block that is more than 2,048 words deep, ESBs drive tri-state lines. Each tri-state line connects all ESBs in a column of MegaLAB structures, and drives the MegaLAB interconnect and row and column FastTrack Interconnect throughout the column. Each ESB incorporates a programmable decoder to activate the tri-state driver appropriately. For instance, to implement 8,192-word-deep memory, four ESBs are used. Eleven address lines drive the ESB memory, and two more drive the tri-state decoder. Depending on which 2,048-word memory page is selected, the appropriate ESB driver is turned on, driving the output to the tri-state line. The Quartus II software automatically combines ESBs with tri-state lines to form deeper memory blocks. The internal tri-state control logic is designed to avoid internal contention and floating lines. See Figure 18.

Input/Output Clock Mode

The input/output clock mode contains two clocks. One clock controls all registers for inputs into the ESB: data input, WE, RE, read address, and write address. The other clock controls the ESB data output registers. The ESB also supports clock enable and asynchronous clear signals; these signals also control the reading and writing of registers independently. Input/output clock mode is commonly used for applications where the reads and writes occur at the same system frequency, but require different clock enable signals for the input and output registers. Figure 21 shows the ESB in input/output clock mode.

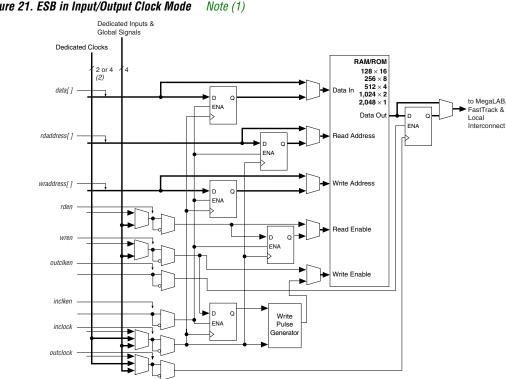


Figure 21. ESB in Input/Output Clock Mode

Notes to Figure 21:

All registers can be cleared asynchronously by ESB local interconnect signals, global signals, or the chip-wide reset. (1)APEX 20KE devices have four dedicated clocks. (2)

Single-Port Mode

The APEX 20K ESB also supports a single-port mode, which is used when simultaneous reads and writes are not required. See Figure 22.

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The APEX 20K device instruction register length is 10 bits. The APEX 20K device USERCODE register length is 32 bits. Tables 20 and 21 show the boundary-scan register length and device IDCODE information for APEX 20K devices.

Table 20. APEX 20K Boundary-Scan Register Length						
Device	Boundary-Scan Register Length					
EP20K30E	420					
EP20K60E	624					
EP20K100	786					
EP20K100E	774					
EP20K160E	984					
EP20K200	1,176					
EP20K200E	1,164					
EP20K300E	1,266					
EP20K400	1,536					
EP20K400E	1,506					
EP20K600E	1,806					
EP20K1000E	2,190					
EP20K1500E	1 (1)					

Note to Table 20:

(1) This device does not support JTAG boundary scan testing.

Device		IDCODE (32 Bits) (1)										
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	1 (1 Bit) (2)								
EP20K30E	0000	1000 0000 0011 0000	000 0110 1110	1								
EP20K60E	0000	1000 0000 0110 0000	000 0110 1110	1								
EP20K100	0000	0000 0100 0001 0110	000 0110 1110	1								
EP20K100E	0000	1000 0001 0000 0000	000 0110 1110	1								
EP20K160E	0000	1000 0001 0110 0000	000 0110 1110	1								
EP20K200	0000	0000 1000 0011 0010	000 0110 1110	1								
EP20K200E	0000	1000 0010 0000 0000	000 0110 1110	1								
EP20K300E	0000	1000 0011 0000 0000	000 0110 1110	1								
EP20K400	0000	0001 0110 0110 0100	000 0110 1110	1								
EP20K400E	0000	1000 0100 0000 0000	000 0110 1110	1								
EP20K600E	0000	1000 0110 0000 0000	000 0110 1110	1								
EP20K1000E	0000	1001 0000 0000 0000	000 0110 1110	1								

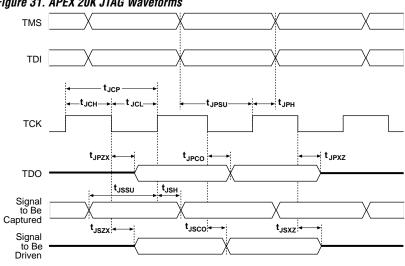
11- 04 00 04 4 ~

Notes to Table 21:

The most significant bit (MSB) is on the left. (1)

(2) The IDCODE's least significant bit (LSB) is always 1.

Figure 31 shows the timing requirements for the JTAG signals.





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For DC Operating Specifications on APEX 20KE I/O standards, please refer to *Application Note 117 (Using Selectable I/O Standards in Altera Devices).*

Table 30. APEX 20KE Device Capacitance Note (15)								
Symbol	Parameter	Conditions	Min	Max	Unit			
C _{IN}	Input capacitance	V _{IN} = 0 V, f = 1.0 MHz		8	pF			
CINCLK	Input capacitance on dedicated clock pin	V _{IN} = 0 V, f = 1.0 MHz		12	pF			
C _{OUT}	Output capacitance	V _{OUT} = 0 V, f = 1.0 MHz		8	pF			

Notes to Tables 27 through 30:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input is -0.5 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 5.75 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) Numbers in parentheses are for industrial-temperature-range devices.
- (4) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically.
- (5) Minimum DC input is -0.5 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to the voltage shown in the following table based on input duty cycle for input currents less than 100 mA. The overshoot is dependent upon duty cycle of the signal. The DC case is equivalent to 100% duty cycle.

Vin	Max. Duty Cycle
4.0V	100% (DC)
4.1	90%

- 4.2 50%
- 4.3 30%
- 4.4 17%
- 4.5 10%
- (6) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.
- (7) Typical values are for $T_A = 25^\circ$ C, $V_{CCINT} = 1.8$ V, and $V_{CCIO} = 1.8$ V, 2.5 V or 3.3 V.
- (8) These values are specified under the APEX 20KE device recommended operating conditions, shown in Table 24 on page 60.
- (9) Refer to Application Note 117 (Using Selectable I/O Standards in Altera Devices) for the V_{IH}, V_{IL}, V_{OH}, V_{OL}, and I_I parameters when VCCIO = 1.8 V.
- (10) The APEX 20KE input buffers are compatible with 1.8-V, 2.5-V and 3.3-V (LVTTL and LVCMOS) signals. Additionally, the input buffers are 3.3-V PCI compliant. Input buffers also meet specifications for GTL+, CTT, AGP, SSTL-2, SSTL-3, and HSTL.
- (11) The I_{OH} parameter refers to high-level TTL, PCI, or CMOS output current.
- (12) The I_{OL} parameter refers to low-level TTL, PCI, or CMOS output current. This parameter applies to open-drain pins as well as output pins.
- (13) This value is specified for normal device operation. The value may vary during power-up.
- (14) Pin pull-up resistance values will be lower if an external source drives the pin higher than V_{CCIO}.
- (15) Capacitance is sample-tested only.

Figure 33 shows the relationship between $\rm V_{CCIO}$ and $\rm V_{CCINT}$ for 3.3-V PCI compliance on APEX 20K devices.

Symbol	-1 Spee	d Grade	-2 Speed Grade		-3 Speed Grade		Units	
							-	
	Min	Max	Min	Max	Min	Max		
t _{SU}	0.1		0.3		0.6		ns	
t _H	0.5		0.8		0.9		ns	
t _{CO}		0.1		0.4		0.6	ns	
t _{LUT}		1.0		1.2		1.4	ns	
t _{ESBRC}		1.7		2.1		2.4	ns	
t _{ESBWC}		5.7		6.9		8.1	ns	
t _{ESBWESU}	3.3		3.9		4.6		ns	
t _{ESBDATASU}	2.2		2.7		3.1		ns	
t _{ESBDATAH}	0.6		0.8		0.9		ns	
t _{ESBADDRSU}	2.4		2.9		3.3		ns	
t _{ESBDATACO1}		1.3		1.6		1.8	ns	
t _{ESBDATACO2}		2.5		3.1		3.6	ns	
t _{ESBDD}		2.5		3.3		3.6	ns	
t _{PD}		2.5		3.1		3.6	ns	
t _{PTERMSU}	1.7		2.1		2.4		ns	
t _{PTERMCO}		1.0		1.2		1.4	ns	
t _{F1-4}		0.4		0.5		0.6	ns	
t _{F5-20}		2.6		2.8		2.9	ns	
t _{F20+}		3.7		3.8		3.9	ns	
t _{CH}	2.0		2.5		3.0		ns	
t _{CL}	2.0		2.5		3.0		ns	
t _{CLRP}	0.5		0.6		0.8		ns	
t _{PREP}	0.5		0.5		0.5		ns	
t _{ESBCH}	2.0		2.5		3.0		ns	
t _{ESBCL}	2.0		2.5		3.0		ns	
t _{ESBWP}	1.5		1.9		2.2		ns	
t _{ESBRP}	1.0		1.2		1.4		ns	

Tables 43 through 48 show the I/O external and external bidirectional timing parameter values for EP20K100, EP20K200, and EP20K400 APEX 20K devices.

Notes to Tables 43 through 48:

- (1) This parameter is measured without using ClockLock or ClockBoost circuits.
- (2) This parameter is measured using ClockLock or ClockBoost circuits.

Tables 49 through 54 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K30E APEX 20KE devices.

Symbol	-	1	-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
t _{SU}	0.01		0.02		0.02		ns
t _H	0.11		0.16		0.23		ns
t _{CO}		0.32		0.45		0.67	ns
t _{LUT}		0.85		1.20		1.77	ns

Symbol	-	1		-2	4	3	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		2.03		2.86		4.24	ns
t _{ESBSRC}		2.58		3.49		5.02	ns
t _{ESBAWC}		3.88		5.45		8.08	ns
t _{ESBSWC}		4.08		5.35		7.48	ns
t _{ESBWASU}	1.77		2.49		3.68		ns
t _{ESBWAH}	0.00		0.00		0.00		ns
t _{ESBWDSU}	1.95		2.74		4.05		ns
t _{ESBWDH}	0.00		0.00		0.00		ns
t _{ESBRASU}	1.96		2.75		4.07		ns
t _{ESBRAH}	0.00		0.00		0.00		ns
t _{ESBWESU}	1.80		2.73		4.28		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	0.07		0.48		1.17		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.30		0.80		1.64		ns
t _{ESBRADDRSU}	0.37		0.90		1.78		ns
t _{ESBDATACO1}		1.11		1.32		1.67	ns
t _{ESBDATACO2}		2.65		3.73		5.53	ns
t _{ESBDD}		3.88		5.45		8.08	ns
t _{PD}		1.91		2.69		3.98	ns
t _{PTERMSU}	1.04		1.71		2.82		ns
t _{PTERMCO}		1.13		1.34		1.69	ns

Table 51. EP20K30E f_{MAX} Routing Delays

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
t _{F1-4}		0.24		0.27		0.31	ns
t _{F5-20}		1.03		1.14		1.30	ns
t _{F20+}		1.42		1.54		1.77	ns

Tables 55 through 60 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K60E APEX 20KE devices.

Table 55. EP20K60E f _{MAX} LE Timing Microparameters									
Symbol	-	1	-2		-3		Unit		
	Min	Max	Min	Max	Min	Max			
t _{SU}	0.17		0.15		0.16		ns		
t _H	0.32		0.33		0.39		ns		
t _{CO}		0.29		0.40		0.60	ns		
t _{LUT}		0.77		1.07		1.59	ns		

Table 57. EP2	Table 57. EP20K60E f _{MAX} Routing Delays									
Symbol	-1		-1 -2		-:	Unit				
	Min	Max	Min	Max	Min	Max				
t _{F1-4}		0.24		0.26		0.30	ns			
t _{F5-20}		1.45		1.58		1.79	ns			
t _{F20+}		1.96		2.14		2.45	ns			

Table 58. EP20K60E Minimum Pulse Width Timing Parameters								
Symbol	-1		-1 -2		-:	Unit		
	Min	Max	Min	Max	Min	Max	-	
t _{CH}	2.00		2.50		2.75		ns	
t _{CL}	2.00		2.50		2.75		ns	
t _{CLRP}	0.20		0.28		0.41		ns	
t _{PREP}	0.20		0.28		0.41		ns	
t _{ESBCH}	2.00		2.50		2.75		ns	
t _{ESBCL}	2.00		2.50		2.75		ns	
t _{ESBWP}	1.29		1.80		2.66		ns	
t _{ESBRP}	1.04		1.45		2.14		ns	

Table 59. EP20K60E External Timing Parameters									
Symbol	-1		I -1 -2		-2	-3	Unit		
	Min	Max	Min	Max	Min	Max			
t _{INSU}	2.03		2.12		2.23		ns		
t _{INH}	0.00		0.00		0.00		ns		
t _{outco}	2.00	4.84	2.00	5.31	2.00	5.81	ns		
t _{INSUPLL}	1.12		1.15		-		ns		
t _{INHPLL}	0.00		0.00		-		ns		
toutcopll	0.50	3.37	0.50	3.69	-	-	ns		

Symbol	-	1	-	-2		3	Unit
	Min	Max	Min	Max	Min	Max	1
t _{ESBARC}		1.65		2.02		2.11	ns
t _{ESBSRC}		2.21		2.70		3.11	ns
t _{ESBAWC}		3.04		3.79		4.42	ns
t _{ESBSWC}		2.81		3.56		4.10	ns
t _{ESBWASU}	0.54		0.66		0.73		ns
t _{ESBWAH}	0.36		0.45		0.47		ns
t _{ESBWDSU}	0.68		0.81		0.94		ns
t _{ESBWDH}	0.36		0.45		0.47		ns
t _{ESBRASU}	1.58		1.87		2.06		ns
t _{ESBRAH}	0.00		0.00		0.01		ns
t _{ESBWESU}	1.41		1.71		2.00		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	-0.02		-0.03		0.09		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	0.14		0.17		0.35		ns
t _{ESBRADDRSU}	0.21		0.27		0.43		ns
t _{ESBDATACO1}		1.04		1.30		1.46	ns
t _{ESBDATACO2}		2.15		2.70		3.16	ns
t _{ESBDD}		2.69		3.35		3.97	ns
t _{PD}		1.55		1.93		2.29	ns
t _{PTERMSU}	1.01		1.23		1.52		ns
t _{PTERMCO}		1.06		1.32		1.04	ns

Symbol	-1 Spee	d Grade	-2 Spee	ed Grade	-3 Spee	d Grade	Unit
	Min	Max	Min	Max	Min	Max	
t _{ESBARC}		1.67		1.91		1.99	ns
t _{ESBSRC}		2.30		2.66		2.93	ns
t _{ESBAWC}		3.09		3.58		3.99	ns
t _{ESBSWC}		3.01		3.65		4.05	ns
t _{ESBWASU}	0.54		0.63		0.65		ns
t _{ESBWAH}	0.36		0.43		0.42		ns
t _{ESBWDSU}	0.69		0.77		0.84		ns
t _{ESBWDH}	0.36		0.43		0.42		ns
t _{ESBRASU}	1.61		1.77		1.86		ns
t _{ESBRAH}	0.00		0.00		0.01		ns
t _{ESBWESU}	1.35		1.47		1.61		ns
t _{ESBWEH}	0.00		0.00		0.00		ns
t _{ESBDATASU}	-0.18		-0.30		-0.27		ns
t _{ESBDATAH}	0.13		0.13		0.13		ns
t _{ESBWADDRSU}	-0.02		-0.11		-0.03		ns
t _{ESBRADDRSU}	0.06		-0.01		-0.05		ns
t _{ESBDATACO1}		1.16		1.40		1.54	ns
t _{ESBDATACO2}		2.18		2.55		2.85	ns
t _{ESBDD}		2.73		3.17		3.58	ns
t _{PD}		1.57		1.83		2.07	ns
t _{PTERMSU}	0.92		0.99		1.18		ns
t _{PTERMCO}		1.18		1.43		1.17	ns

Symbol	-1 Spee	d Grade	irade -2 Speed Grade		-3 Spee	Unit	
	Min	Max	Min	Max	Min	Max	
t _{CH}	2.00		2.50		2.75		ns
t _{CL}	2.00		2.50		2.75		ns
t _{CLRP}	0.18		0.26		0.34		ns
t _{PREP}	0.18		0.26		0.34		ns
t _{ESBCH}	2.00		2.50		2.75		ns
t _{ESBCL}	2.00		2.50		2.75		ns
t _{ESBWP}	1.17		1.68		2.18		ns
t _{ESBRP}	0.95		1.35		1.76		ns

Symbol	-1 Speed Grade		-1 Speed Grade -2 Speed Grade		d Grade	-3 Speed	Unit
	Min	Max	Min	Max	Min	Max	1
t _{INSU}	2.74		2.74		2.87		ns
t _{INH}	0.00		0.00		0.00		ns
toutco	2.00	5.51	2.00	6.06	2.00	6.61	ns
tINSUPLL	1.86		1.96		-		ns
t _{INHPLL}	0.00		0.00		-		ns
toutcopll	0.50	2.62	0.50	2.91	-	-	ns

Symbol	-1 Speed Grade		-2 Spee	d Grade	-3 Spee	Unit	
	Min	Max	Min	Max	Min	Max	1
t _{insubidir}	0.64		0.98		1.08		ns
t _{inhbidir}	0.00		0.00		0.00		ns
toutcobidir	2.00	5.51	2.00	6.06	2.00	6.61	ns
t _{xzbidir}		6.10		6.74		7.10	ns
t _{zxbidir}		6.10		6.74		7.10	ns
t _{insubidirpll}	2.26		2.68		-		ns
t _{inhbidirpll}	0.00		0.00		-		ns
toutcobidirpll	0.50	2.62	0.50	2.91	-	-	ns
t _{xzbidirpll}		3.21		3.59		-	ns
t _{ZXBIDIRPLL}		3.21		3.59		-	ns

Tables 97 through 102 describe f_{MAX} LE Timing Microparameters, f_{MAX} ESB Timing Microparameters, f_{MAX} Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K1000E APEX 20KE devices.

Table 97. EP2	Table 97. EP20K1000E f _{MAX} LE Timing Microparameters									
Symbol	-1 Speed Grade		-2 Spec	ed Grade	-3 Spee	d Grade	Unit			
	Min	Мах	Min	Max	Min	Max				
t _{SU}	0.25		0.25		0.25		ns			
t _H	0.25		0.25		0.25		ns			
t _{CO}		0.28		0.32		0.33	ns			
t _{LUT}		0.80		0.95		1.13	ns			

SRAM configuration elements allow APEX 20K devices to be reconfigured in-circuit by loading new configuration data into the device. Real-time reconfiguration is performed by forcing the device into command mode with a device pin, loading different configuration data, reinitializing the device, and resuming usermode operation. In-field upgrades can be performed by distributing new configuration files.

Configuration Schemes

The configuration data for an APEX 20K device can be loaded with one of five configuration schemes (see Table 111), chosen on the basis of the target application. An EPC2 or EPC16 configuration device, intelligent controller, or the JTAG port can be used to control the configuration of an APEX 20K device. When a configuration device is used, the system can configure automatically at system power-up.

Multiple APEX 20K devices can be configured in any of five configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Table 111. Data Sources for Configuration					
Configuration Scheme	Data Source				
Configuration device	EPC1, EPC2, EPC16 configuration devices				
Passive serial (PS)	MasterBlaster or ByteBlasterMV download cable or serial data source				
Passive parallel asynchronous (PPA)	Parallel data source				
Passive parallel synchronous (PPS)	Parallel data source				
JTAG	MasterBlaster or ByteBlasterMV download cable or a microprocessor				
	with a Jam or JBC File				



For more information on configuration, see *Application Note* 116 (*Configuring APEX 20K, FLEX 10K, & FLEX 6000 Devices.*)

Device Pin-Outs

See the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information

Revision History

The information contained in the *APEX 20K Programmable Logic Device Family Data Sheet* version 5.1 supersedes information published in previous versions.

Version 5.1

APEX 20K Programmable Logic Device Family Data Sheet version 5.1 contains the following changes:

- In version 5.0, the VI input voltage spec was updated in Table 28 on page 63.
- In version 5.0, *Note* (5) to Tables 27 through 30 was revised.
- Added *Note* (2) to Figure 21 on page 33.

Version 5.0

APEX 20K Programmable Logic Device Family Data Sheet version 5.0 contains the following changes:

- Updated Tables 23 through 26. Removed 2.5-V operating condition tables because all APEX 20K devices are now 5.0-V tolerant.
- Updated conditions in Tables 33, 38 and 39.
- Updated data for t_{ESBDATAH} parameter.

Version 4.3

APEX 20K Programmable Logic Device Family Data Sheet version 4.3 contains the following changes:

- Updated Figure 20.
- Updated *Note* (2) to Table 13.
- Updated notes to Tables 27 through 30.

Version 4.2

APEX 20K Programmable Logic Device Family Data Sheet version 4.2 contains the following changes:

- Updated Figure 29.
- Updated *Note* (1) to Figure 29.